

Amendment "A" page 2 of 11
10/628,986

DOCKET NO. 03-0593
81577(6653)

Amendments to the Specification:

Replace the paragraph beginning on page 11, line 25 as follows:

--In step 218, the comparison matrix values 802 of the third combined matrix 800 in FIG. 8 are filtered and adjusted, for example, to display areas of the integrated circuit die to concentrate on for defect analysis. By way of example, the comparison matrix values 802 of the third combined matrix 800 in FIG. 8 may be filtered and adjusted by calculating the reciprocal of the comparison matrix values 802 from [[of]] the third combined matrix 800.--

Replace the Abstract beginning on page 20, line 3 as follows:

--A method of mapping logic failures in an integrated circuit die includes steps of. (a) generating a navigation map of test paths for an integrated circuit die, [[; (b)]] selecting a grid spacing to define a grid map of cell locations from the navigation map for each of the test paths, [[;]] and [[(c)]] calculating a value for each of the cell locations that wherein the value is representative of the difference between a total number of the test paths intersecting each of the cell locations and a failed number of the test paths intersecting each of the cell locations.--